



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Henry A. Hill
Serial No. : 10/616,504
Filed : July 8, 2003
Title : CYCLIC ERROR COMPENSATION IN INTERFEROMETRY SYSTEMS

Art Unit : 2877
Examiner : Unknown

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

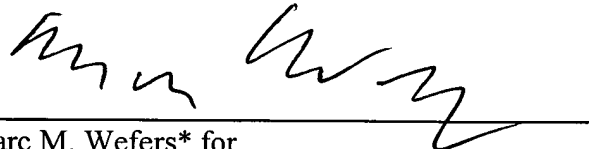
INFORMATION DISCLOSURE STATEMENT

Applicant submits the references listed on the attached form PTO-1449. A copy of a communication from a foreign patent office in a counterpart application is also enclosed.

This statement is being filed before the receipt of a first Office action on the merits. Please apply any charges or credits to Deposit Account No. 06-1050, referencing Attorney Docket No. 09712-330001.

Respectfully submitted,

Date: 12/1/03



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*See attached document certifying that Marc M. Wefers has limited recognition to practice before the U.S. Patent and Trademark Office under 37 C.F.R. § 10.9(b).

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CERTIFICATE OF MAILING BY FIRST CLASS MAIL

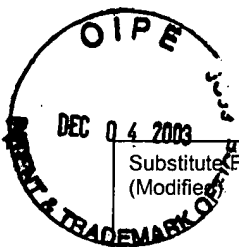
I hereby certify under 37 CFR §1.8(a) that this correspondence is being deposited with the United States Postal Service as first class mail with sufficient postage on the date indicated below and is addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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Substitute Form PTO-1449
(Modified)U.S. Department of Commerce
Patent and Trademark OfficeAttorney's Docket No.
09712-330001Application No.
10/616,504**Information Disclosure Statement
by Applicant**

(Use several sheets if necessary)

(37 CFR §1.98(b))

Applicant
Henry A. HillFiling Date
July 8, 2003Group Art Unit
2877**U.S. Patent Documents**

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	6,252,668	06/26/2001	Hill	356	487	
	AB						
	AC						
	AD						

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AE	0 514 579 A1	11/25/1992	EPO	G01J	9/04		
	AF	0 689 030 A2	12/27/1995	EPO	G01B	9/02		
	AG	DE 40 31 291 A1	06/04/1992	Germany	G01B	9/02	Abstract Only	
	AH							
	AI							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AJ	Norman Bobroff, "Residual errors in laser interferometry from air turbulence and nonlinearity", <u>Applied Optics</u> , Vol. 26, No. 13, pp. 2676-2682
	AK	Mitsuru Tanaka, et al., "Linear Interpolation of Periodic Error in a Heterodyne Laser Interferometer at Subnanometer Levels", <u>IEEE Transactions on Instrumentation and Measurement</u> , Vol. 38, No. 2, pp. 553-554 (April 1989)
	AL	Chien-Ming Wu et al., "Analytical modeling of the periodic nonlinearity in heterodyne interferometry", <u>Applied Optics</u> , Vol. 37, No. 28, pp. 6696-6700 (October 1, 1998)
	AM	Chien-Ming Wu et al., "Nonlinearity in measurements of length by optical interferometry", <u>Measurement Science and Technology</u> , Vol. 7, No. 1, pp. 62-68 (January 1996)
	AN	
	AO	

Examiner Signature

Date Considered

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.